



APPROVAL SHEET

Approval Specification	Customer's Approval Certificate
TO: Part No.: Customer's Part No.:	Please return this copy as a certification of your approval Checked & Approved by: Date:

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Part No.	:	SF0425
Pages	:	6
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Revision	:	1.0

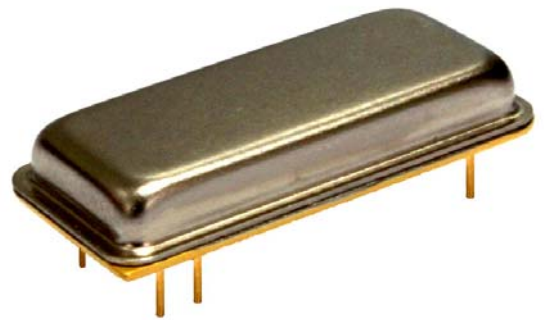
Prepared by:	梁浩
Checked by:	
Approved by:	

Application

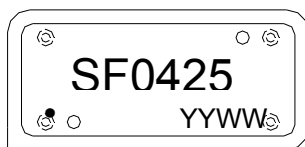
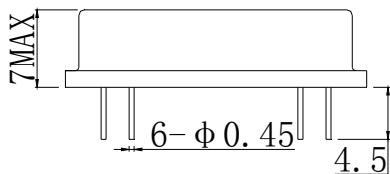
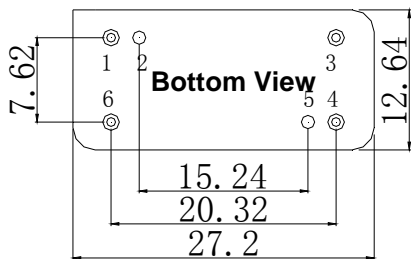
- Low-loss SAW component
- Low amplitude ripple
- Sharp rejections at both out-bands
- Usable passband 10 MHz

Features

- RoHS compatible
- Package size 27.2x12.64x7.00mm³
- Package Code DIP2712J
- Electrostatic Sensitive Device(ESD)



Package Dimensions (Unit: mm)



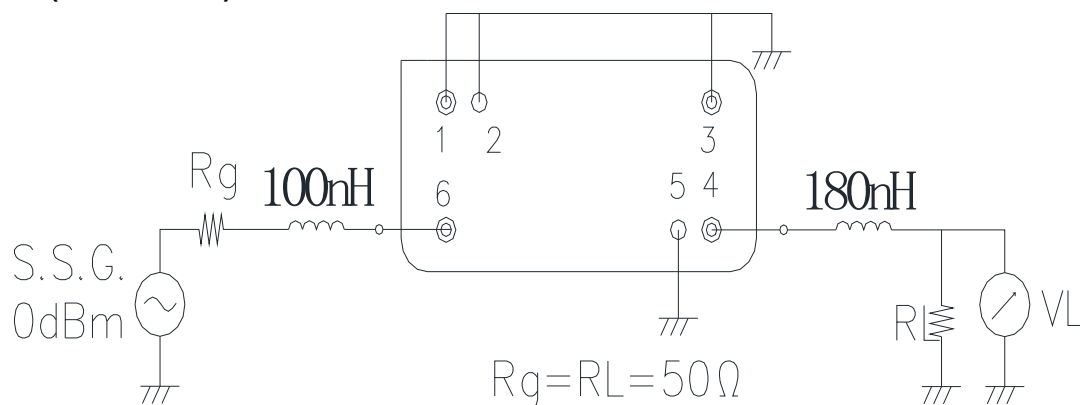
Pin Configuration

Pin No.	Description
6	Input
4	Output
1,2,3,5	Ground

Marking Description

S	Trademark
F	SAW Filter
0425	Part Number
●	Pin 1
YYWW	Year Code & Week Code

Test Circuit(Bottom View)



*Fig: If the products produced in 06th week of 2012, The year code & week code is 1206.

Performance**Maximum Rating**

Item		Value	Unit
DC Voltage	V_{DC}	3	V
Operation Temperature	T	-40 ~ +85	°C
Storage Temperature	T_{stg}	-55 ~ +125	°C
RF Power Dissipation	P	10	dBm

Electronic Characteristics

Test Temperature: $25^{\circ}\text{C} \pm 2^{\circ}\text{C}$

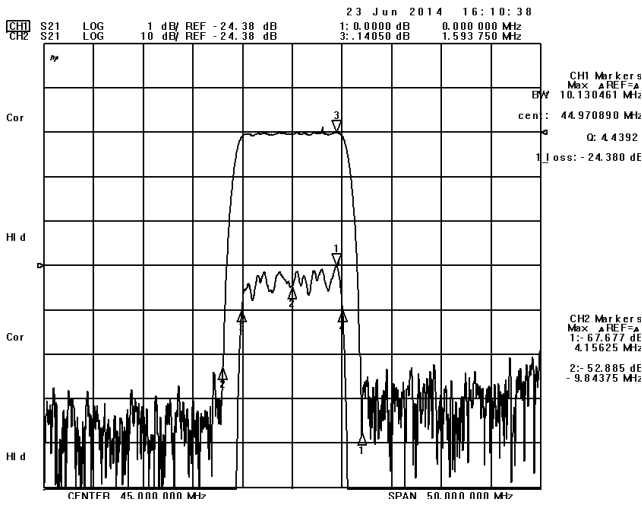
Terminating source impedance: 50Ω

Terminating load impedance: 50Ω

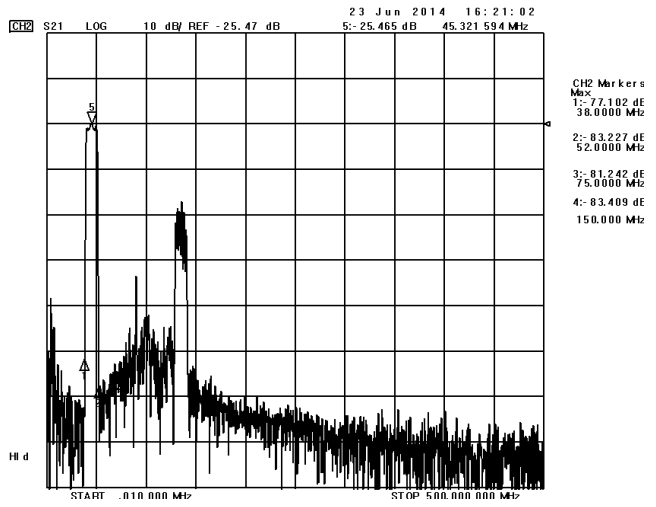
Item		Minimum	Typical	Maximum	Unit
Center Frequency	f_c	44.9	45.0	45.1	MHz
Insertion Loss(min)	IL		24.4	25.0	dB
1 dB Bandwidth	BW_{1dB}	10.0	10.1		MHz
Absolute Attenuation	α				
	38.00MHz	50.0	52.0		dB
	52.00MHz	50.0	67.0		dB

Frequency Characteristics

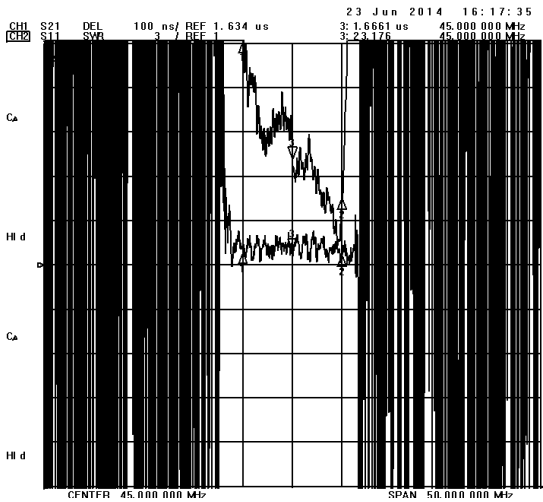
Frequency Response



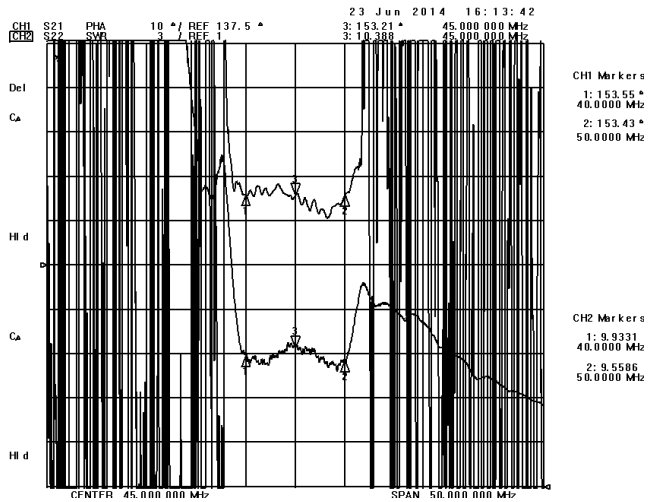
Frequency Response (wideband)



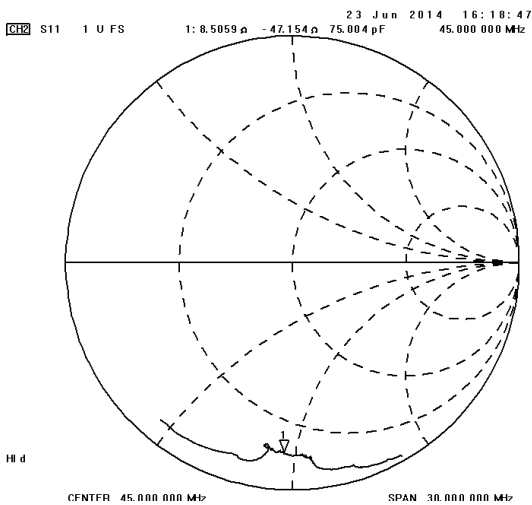
Delay Ripple & S11 VSWR



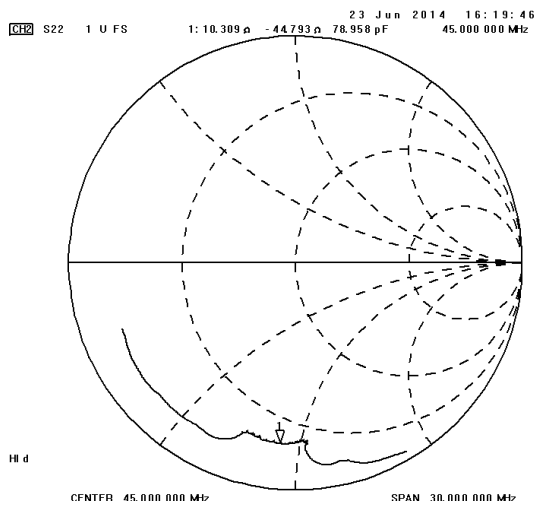
Phase Linearity & S22 VSWR



S11 Smith Chart

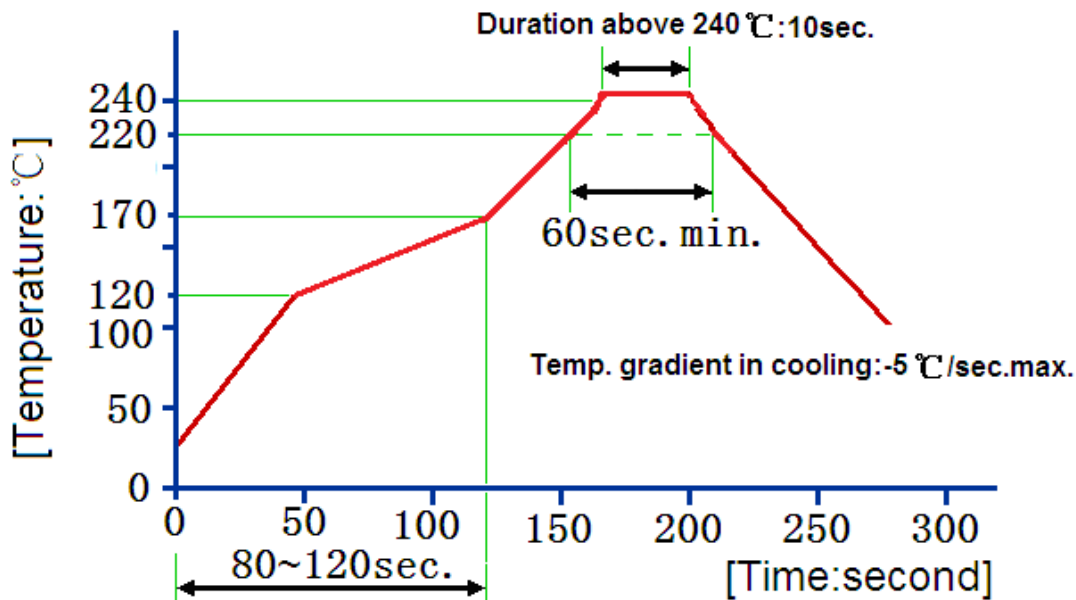


S22 Smith Chart



Reliability (The SAW components shall remain electrical performance after tests)

No.	Test item	Test condition
1	Temperature Storage	(1) Temperature: $85^{\circ}\text{C}\pm 2^{\circ}\text{C}$, Duration: 250h , Recovery time: $2\text{h}\pm 0.5\text{h}$ (2) Temperature: $-55^{\circ}\text{C}\pm 3^{\circ}\text{C}$, Duration: 250h ,Recovery time: $2\text{h}\pm 0.5\text{h}$
2	Humidity Test	Conditions: $60^{\circ}\text{C}\pm 2^{\circ}\text{C}$, 90~95% RH Duration: 250h
3	Thermal Shock	Heat cycle conditions: TA= $-55^{\circ}\text{C}\pm 3^{\circ}\text{C}$, TB= $85^{\circ}\text{C}\pm 2^{\circ}\text{C}$, t1=t2=30min, Switch time: $\leq 3\text{min}$, Cycle time: 100 times, Recovery time: $2\text{h}\pm 0.5\text{h}$.
4	Vibration Fatigue	Frequency of vibration: 10~55Hz Amplitude:1.5mm Directions: X,Y and Z Duration: 2h
5	Drop Test	Cycle time: 10 times Height: 1.0m
6	Solder Ability Test	Temperature: $245^{\circ}\text{C}\pm 5^{\circ}\text{C}$ Duration: 3.0s--5.0s Depth: DIP--2/3 , SMD--1/5
7	Resistance to Soldering Heat	(1)Thickness of PCB:1mm , Solder condition: $260^{\circ}\text{C}\pm 5^{\circ}\text{C}$, Duration: $10\pm 1\text{s}$ (2)Temperature of Soldering Iron: $350^{\circ}\text{C}\pm 10^{\circ}\text{C}$, Duration: 3~4s , Recovery time : $2 \pm 0.5\text{h}$

Recommended Reflow Soldering Diagram**Reflow cycles: 3 cycles max.**

Notes

1. As a result of the particularity of inner structure of SAW products, it easy to be breakdown by electrostatic, so we should pay attention to **ESD protect** in the test.
2. **Static voltage** between signal load and ground may cause deterioration and destruction of the component. Please avoid static voltage.
3. **Ultrasonic cleaning** may cause deterioration and destruction of the component. Please avoid ultrasonic cleaning.
4. Only leads of component may **be soldered**. Please avoid soldering another part of component.
5. There is a close relationship between the device's performance and **matching network**. The specifications of this device are based on the test circuit shown above. L and C values may change depending on board layout. Values shown are intended as a guide only.